

RELIABILITY REPORT





Reliability Data Report Product Family R378

LT1797 \ LT1800 \ LT1801 \ LT1802 \
LT1803 \ LT1804 \ LT1805 \ LT1806 \
LT1807 \ LT1809 \ LT1810 \ LT1812 \
LT1813 \ LT1814 \ LT1815 \ LT1816 \
LT1817 \ LT1818 \ LT1819 \ LT1969 \
LT6200 \ LT6201 \ LT6202 \ LT6203 \
LT6204 \ LT6205 \ LT6206 \ LT6207 \
LT6210 \ LT6220 \ LT6221 \ LT6230 \
LT6231 \ LT6232 \ LT6233 \ LT6234 \
LT6235 \ LT6236 \ LT6237 \ LT6238 \
LT6350 \ LT6411 \ LT6550 \ LT6551 \
LT6552 \ LT6553 \ LT6554 \ LT6557 \
LT6559

Reliability Data Report

Report Number: R378

Report generated on: Fri Oct 30 15:56:57 PDT 2020

OPERATING LIFE TEST					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+125°C) ¹	No. of FAILURES ^{2, 3}
SSOP/TSSOP	154	0421	0421	27.6	0
SOIC/SOT/MSOP	4,147	9914	1348	716.7	0
PLASTIC DIP	77	0630	0630	13.8	0
QFN/DFN	77	0630	0630	13.8	0
FLATPACK	157	0414	1051	15.2	0
Totals	4,612	-	-	787.1	0

PRESSURE COOKER TEST AT 15 PSIG , +121 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
QFN/DFN	2,221	0231	1349	156.0	0
SSOP/TSSOP	1,603	0205	1402	163.3	0
SOIC/SOT/MSOP	39,550	9905	1706	3,981.4	0
Totals	43,374	-	-	4,300.7	0

TEMP CYCLE FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
QFN/DFN	2,173	0231	1650	459.0	0
SSOP/TSSOP	1,081	0205	1402	445.8	0
SOIC/SOT/MSOP	21,138	9905	1706	6,987.4	0
FLATPACK	17	0414	0414	1.7	0
Totals	24,409	-	-	7,893.7	0

THERMAL SHOCK FROM -65 TO 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
QFN/DFN	2,105	0231	1650	329.5	0
SSOP/TSSOP	1,270	0205	1402	373.9	0
SOIC/SOT/MSOP	29,638	9905	1706	8,124.0	0
FLATPACK	17	0414	0414	0.3	0
Totals	33,030	-	-	8,827.7	0

HIGH TEMPERATURE BAKE AT 150 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
SSOP/TSSOP	80	0820	0829	80	0
SOIC/SOT/MSOP	1,503	0751	1430	1,493.0	0
QFN/DFN	100	0851	1349	100	0
Totals	1,683	-	-	1,673	0

(1) Assumes Activation Energy = 1.0 Electron Volts
 (2) Failure Rate Equivalent to +55 °C, 60% Confidence Level = 2.3 FITS
 (3) Mean Time Between Failure in Years = 49325.85

Note 1: 1 FIT = 1 Failure in One Billion Hours.

Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL Preconditioning

Reliability Data Report

Report Number: R378

Report generated on: Mon Jul 13 15:56:57 PDT 2015

HIGH TEMPERATURE BAKE AT 175 DEG C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
SOIC/SOT/MSOP	1,125	1325	1516	1,050.0	0
Totals	1,125	-	-	1,050.0	0